CLAIMS

[1] A method for producing a Group III nitride crystal comprising:
growing a crystal in a nitrogen-containing atmosphere by reacting at
least one Group III element selected from Ga, Al, and In with nitrogen in a
melt that includes a flux including an alkali metal,

wherein the flux further includes Mg.

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- [2] The method according to claim 1, wherein Mg of the flux functions as at least one of a flux component and a doping component.
- [3] The method according to claim 1, wherein the flux includes as a doping component at least one selected from an alkaline-earth metal (other than Mg) and Zn in addition to or instead of Mg.
 - [4] The method according to claim 1, wherein the nitrogen is supplied as a nitrogen-containing gas.
- [5] The method according to claim 3, wherein the alkaline-earth metal is at least one selected from Ca, Be, Sr, and Ba.
 - [6] The method according to claim 1, wherein the flux is a mixed flux of Na and Mg.
 - [7] The method according to claim 6, wherein a proportion of Mg in the mixed flux is 0.001 to 10 mol%.
- 20 [8] The method according to claim 6, wherein the Group III element is Ga and the Group III nitride is GaN.
 - [9] A Group III nitride crystal produced by the method according to claim 1.
- [10] The Group III nitride crystal according to claim 9, wherein a doping amount of Mg is more than 0 and not more than 1×10^{20} cm⁻³.
 - [11] The Group III nitride crystal according to claim 9, wherein a total doping amount of Mg, the alkaline-earth metal (other than Mg), and Zn is more than 0 and not more than 1×10^{17} cm⁻³.
- [12] The Group III nitride crystal according to claim 9, wherein an oxygen concentration of the crystal is 0 to 1×10^{17} cm⁻³.

- [13] The Group III nitride crystal according to claim 9, wherein a resistivity (specific resistance) is not less than $1 \times 10^3 \,\Omega$ ·cm.
- [14] The Group III nitride crystal according to claim 9, wherein a resistivity (specific resistance) is not less than $1 \times 10^5 \,\Omega$ ·cm.
- 5 [15] A Group III nitride substrate comprising the Group III nitride crystal according to claim 9.
 - [16] The Group III nitride substrate according to claim 15, wherein the substrate is a p-type substrate or a semi-insulating substrate.
- [17] A field-effect transistor comprising the Group III nitride substrate 10 according to claim 16.